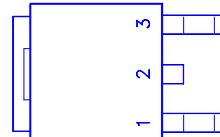
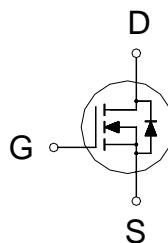


NIKO-SEM
**N-Channel Logic Level Enhancement
Mode Field Effect Transistor**
P5506BDG
TO-252
Lead-Free
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
60	55m	10A

**ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	10	A
		8	
Pulsed Drain Current ¹	I_{DM}	32	
Power Dissipation	P_D	32	W
		22	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	$^\circ\text{C}$
Lead Temperature (1/16" from case for 10 sec.)	T_L	275	

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		3	$^\circ\text{C} / \text{W}$
Junction-to-Ambient	$R_{\theta JA}$		75	$^\circ\text{C} / \text{W}$

¹Pulse width limited by maximum junction temperature.²Duty cycle $\leq 1\%$ **ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.5	2.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 48V, V_{GS} = 0V$			1	μA
		$V_{DS} = 40V, V_{GS} = 0V, T_J = 55^\circ\text{C}$			10	

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On-State Drain Current ¹	I _{D(ON)}	V _{DS} = 5V, V _{GS} = 10V	32			A
Drain-Source Resistance ¹	On-State R _{DS(ON)}	V _{GS} = 4.5V, I _D = 8A		59	75	m
		V _{GS} = 10V, I _D = 10A		42	55	
Forward Transconductance ¹	g _{fs}	V _{DS} = 10V, I _D = 10A		14		S

DYNAMIC

Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz		650		pF
Output Capacitance	C _{oss}			80		
Reverse Transfer Capacitance	C _{rss}			35		
Total Gate Charge ²	Q _g	V _{DS} = 0.5V _{(BR)DSS} , V _{GS} = 10V, I _D = 4.5A		12.5	18	nC
Gate-Source Charge ²	Q _{gs}			2.4		
Gate-Drain Charge ²	Q _{gd}			2.6		
Turn-On Delay Time ²	t _{d(on)}	V _{DD} = 30V I _D ≈ 1A, V _{GS} = 10V, R _{GEN} = 6		11	20	ns
Rise Time ²	t _r			8	18	
Turn-Off Delay Time ²	t _{d(off)}			19	35	
Fall Time ²	t _f			6	15	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_C = 25 °C)

Continuous Current	I _S			1.3		A
Pulsed Current ³	I _{SM}			2.6		
Forward Voltage ¹	V _{SD}	I _F = 1A, V _{GS} = 0V		1	V	

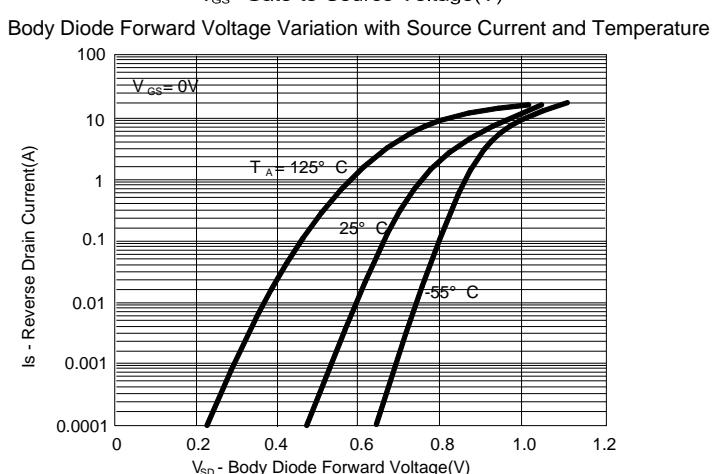
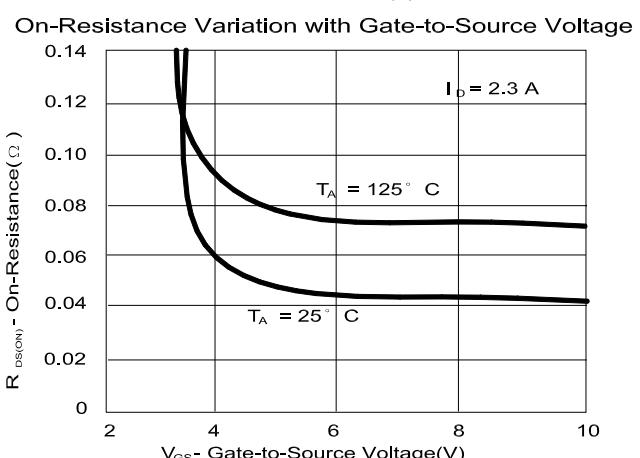
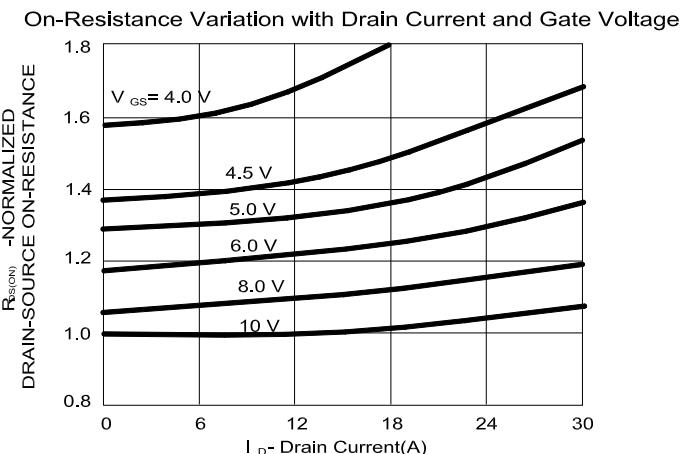
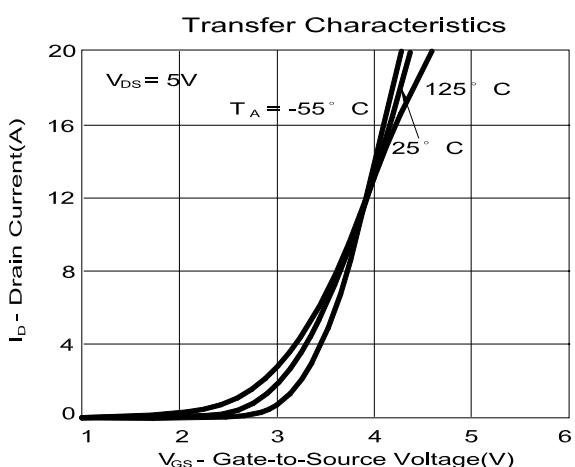
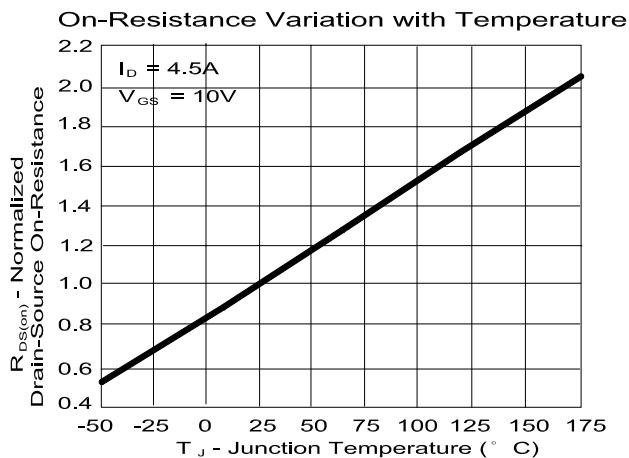
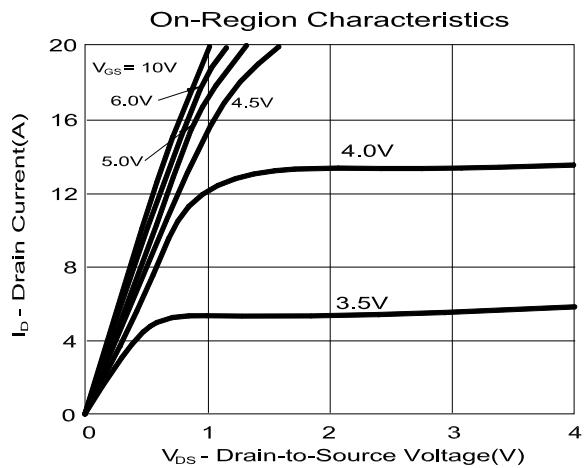
¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.**REMARK: THE PRODUCT MARKED WITH “P5506BDG”, DATE CODE or LOT #**

Orders for parts with Lead-Free plating can be placed using the PXXXXXXG parts name.

NIKO-SEM

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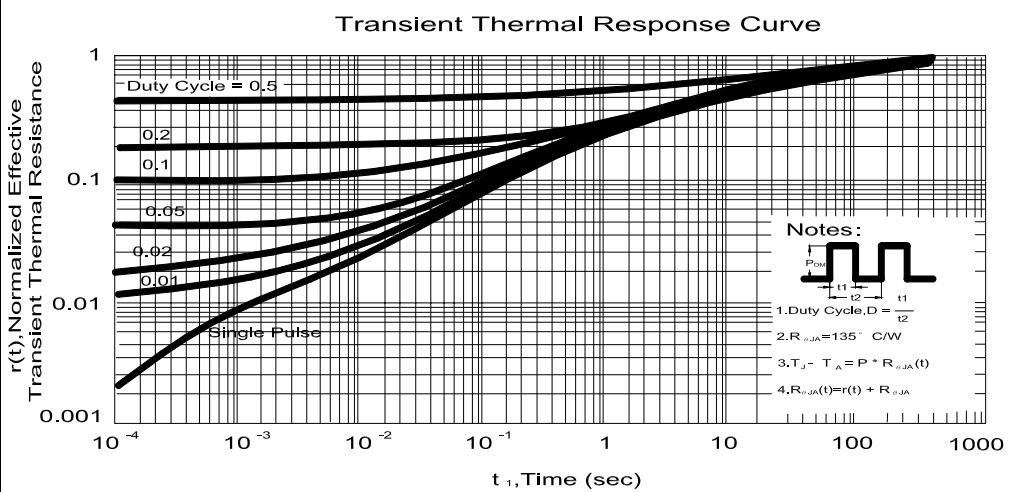
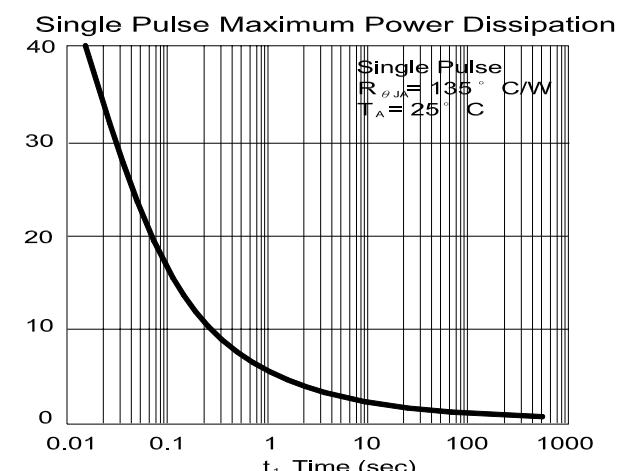
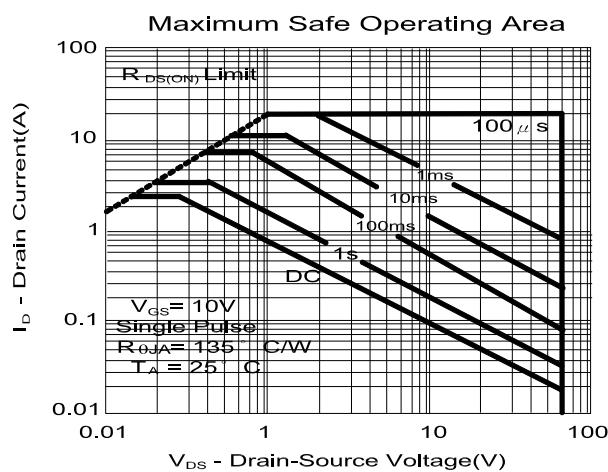
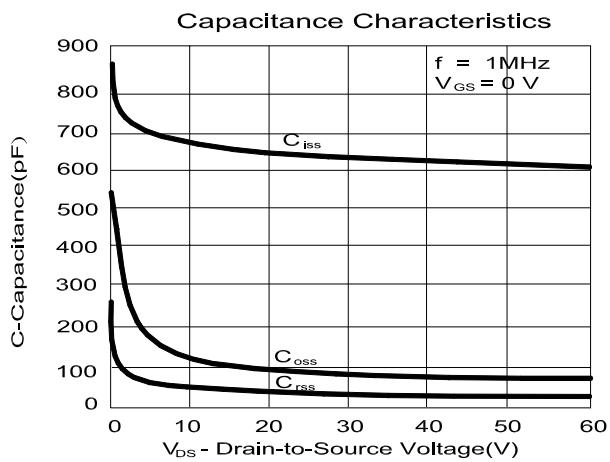
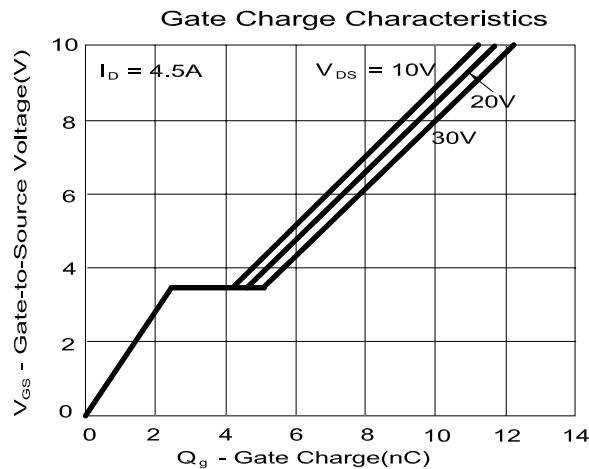
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TO-252 (DPAK) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	9.35		10.4	H	0.89		2.03
B	2.2		2.4	I	6.35		6.80
C	0.45		0.6	J	5.2		5.5
D	0.89		1.5	K	0.6		1
E	0.45		0.69	L	0.5		0.9
F	0.03		0.23	M	3.96	4.57	5.18
G	5.2		6.2	N			

